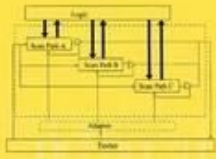


# Power-Constrained Testing of VLSI Circuits

by  
Nicola Nicolici and Bashir M. Al-Hashimi



Kluwer Academic Publishers

# Power-Constrained Testing of VLSI Circuits : A Guide to the IEEE 1149.4 Test Standard

Nicola Nicolici, Bashir M. Al-Hashimi



This text focuses on techniques for minimizing power dissipation during test application at logic and register-transfer levels of abstraction of the VLSI design flow. It surveys existing techniques and presents several test automation techniques for reducing power in scan-based sequential circuits and BIST data paths.

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